

**PATENT APPLICATION**  
Sheet 1 of 1

<b>FORM PTO-1449</b>  <b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b>  (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO. #2
	10010274-1	
	APPLICANT <b>Wing J. Mar and Joseph M. Gorin</b>	
	FILING DATE	GROUP
	herewith	

10872 U.S. PTO  
09/22/05  
08/01/01

**REFERENCE DESIGNATION U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	1A				
	1B				
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION	
						YES	NO
	1L						
	1M						
	1N						
	1O						
	1P						

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

7.12	1Q	Mouthrup, Andrew A. and Muha, Michael S., Accurate Measurement of Signals Close to the Noise Floor of a Spectrum Analyzer, IEEE Transactions on Microwave Theory and Techniques, Vol. 39, No. 11, November 1991, pg. 1882 - 1885.
	1R	
	1S	

EXAMINER	DATE CONSIDERED 12/20/05
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FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

10010274-1

SERIAL NO.

09/922,065

APPLICANT

Wing Jong Mar, et al.

FILING DATE

Aug. 1, 2001

GROUP

2631

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME
	1A			
	1B			
	1C			
	1D			
	1E			
	1F			
	1G			
	1H			
	1I			
	1J			
	1K			

RECEIVED

MAY 23 2002

Technology Center 2600

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO
	1L					
	1M					
	1N					
	1O					
	1P					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

TW	1Q	Rhode & Schwarz Data Sheet for "Phase Noise Measurement Software FS-K4" for use with Spectrum Analyzer Models FSE/FSIQ/FSP/FSU.
TW	1R	Rhode & Schwarz help menus for using phase noise measurement software, Figs. 1-3, including "Making a Phase Noise Measurement".
	1S	

EXAMINER

DATE CONSIDERED

12/20/04